Case No.: 58065US008

Amendment to the Specification:

Please amend the paragraph on page 16, line 1 beginning with the word "The" and ending with the word "2m" as follows:

The next steps involve creating features in thinned dielectric layer 212'. Initially, photoresist is applied to both sides of the existing structure. Phototools are aligned to the metal patterns on each side of the laminate structure and both layers of photoresist are imaged by exposure to suitable radiation and developed in the same manner as previously described. This results in patterned photoresist layers 224 and 226 aligned to circuit traces 220 and etched metal substrate 210, respectively, as illustrated in Fig. 2j. Next, the exposed portions of dielectric layer [[212]] 212' are shaped or removed by exposure to, e.g., plasma or chemical etchants, and the remaining portions of photoresist layers 224 and 226 are removed to leave the flexure structure illustrated in Fig. 2k. Suitable methods are known to those skilled in the art. Subsequently, another layer, or layers, of photoresist may be applied, imaged and developed, on one or both sides of the structure to allow circuit traces 220 to be plated with an additional layer of conductive material 228 suitable for electrical bonding or contact compatibility, e.g., gold, as illustrated in Fig. 21. Optionally, as a final step, a layer of covercoat 230 may be applied, exposed and developed to form a protective layer over circuit traces 220, as illustrated in Fig. 2m.